DESCRIPTION

The MP1918 is a 100V half-bridge driver designed to drive enhancement mode Gallium Nitride (GaN) FETs or N-channel MOSFETs with a low gate threshold voltage in a half-bridge or synchronous application.

The MP1918 features independent high-side (HS) and low-side (LS) pulse-width modulation (PWM) inputs. It also provides a bootstrap technique for the HS driver voltage, and can operate up to 100V. The new charging technology prevents the HS driver voltage from exceeding the VCC voltage (V_{CC}), which prevents the gate voltage from exceeding the GaN FET's maximum gate-to-source voltage rating.

The MP1918 has two separate gate outputs, allowing the turn-on and turn-off capabilities to be independently adjusted by adding an impedance to the gate loop. The MP1918 can operate up to several MHz.

The MP1918 is available in a QFN-14 (3mmx3mm) package with wettable flanks.

FEATURES

- Independent High-Side (HS) and Low-Side (LS) TTL Logic Inputs
- HS Floating Bias Voltage Rail Operates Up to 100V_{DC}
- Separate Gate Outputs for Adjustable Turn-On and Turn-Off Capabilities
- Internal Bootstrap Switch Supply Voltage Clamping
- 3.7V to 5.5V VCC Voltage (V_{CC}) Range
- 0.27Ω/1.2Ω Pull-Down/Pull-Up Resistance
- Fast Propagation Times
- Excellent Propagation Delay Matching (Typically 1.5ns)
- Available in a QFN-14 (3mmx3mm) Package with Wettable Flanks

APPLICATIONS

- Half-Bridge and Full-Bridge Converters
- Audio Class-D Amplifiers
- Synchronous Buck Converters
- Power Modules

TYPICAL APPLICATION
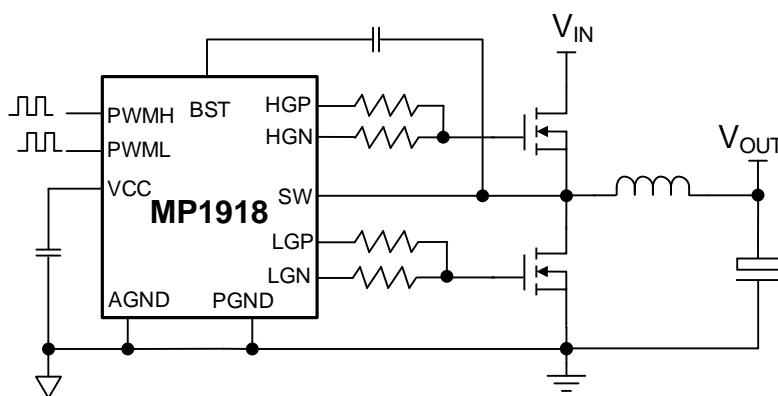
ORDERING INFORMATION

Part Number*	Package	Top Marking	MSL Rating
MP1918GQE	QFN-14 (3mmx3mm)	*See Below*	1

* For Tape & Reel, add suffix -Z (e.g. MP1918GQE-Z).

TOP MARKING

$\overline{\text{BRTY}}$

LLLL

BRT: Product code of MP1918GQE-Z
Y: Year code
LLLL: Lot number

PACKAGE REFERENCE

TOP VIEW

QFN-14 (3mmx3mm) with Wettable Flanks
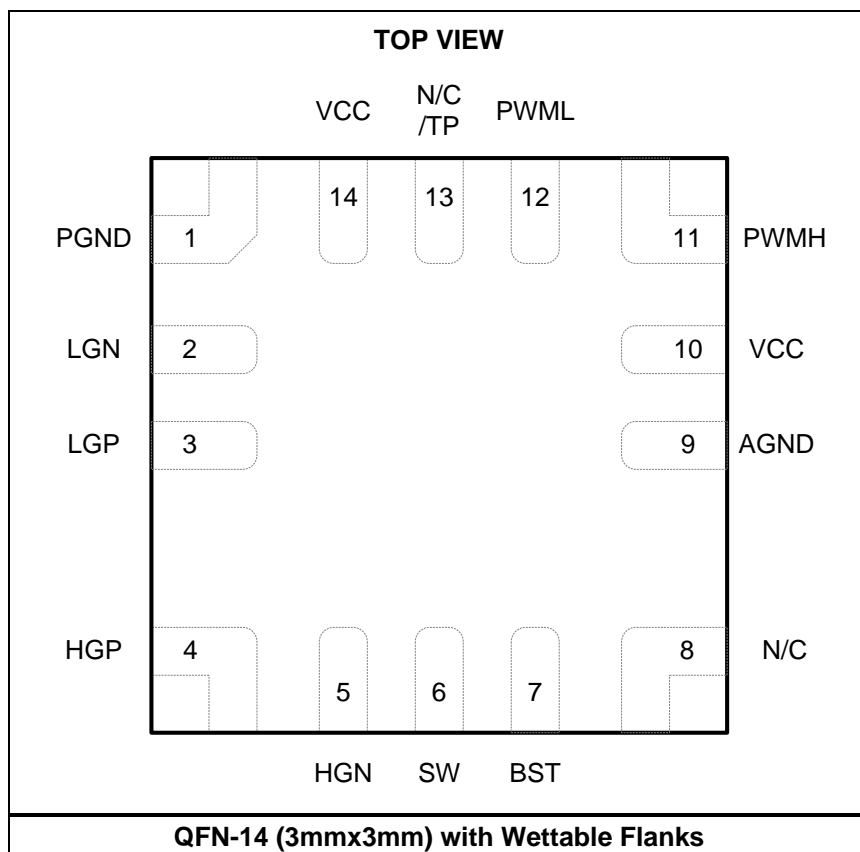
PIN FUNCTIONS

Pin #	Name	Description
1	PGND	**Power ground.**
2	LGN	**Low-side (LS) gate driver sink current output.** Connect the LGN pin to the gate of the low-side MOSFET (LS-FET) with a short or a resistor to adjust the turn-off speed.
3	LGP	**LS gate driver source current output.** Connect the LGP pin to the LS-FET's gate with a short or a resistor to adjust the turn-on speed.
4	HGP	**High-side (HS) gate driver source current output.** Connect the HGP pin to the gate of the high-side MOSFET (HS-FET) with a short or a resistor to adjust the turn-on speed.
5	HGN	**HS gate driver sink current output.** Connect the HGN pin to the HS-FET's gate with a short or a resistor to adjust the turn-off speed.
6	SW	**Switching node**. The SW pin is the HS-FET's source connection and the bootstrap capacitor's negative terminal.
7	BST	**HS gate driver bootstrap rail.** Place a capacitor between the BST and SW pins, and as close as possible to the pins.
8	N/C	**No connection.**
9	AGND	**IC signal ground.**
10, 14	VCC	**5V driver supply.** Place a low-ESL/ESR MLCC decoupling capacitor from the VCC pin to GND.
11	PWMH	**HS driver PWM input**
12	PWML	**LS driver PWM input**
13	N/C/TP	**No connection.**

ABSOLUTE MAXIMUM RATINGS [1]

Supply voltage (V_{CC}) (DC)............-0.3V to +6.5V
Supply voltage (V_{CC}) (25ns) ....-0.3V to +8V
V_{BST-SW} (DC)................................ -0.3V to +6.5V
V_{BST-SW} (25ns) ....-0.3V to +8V
V_{SW} (DC).................................... -0.3V to +105V
V_{SW} (20ns) ....-5V to +108V
$V_{BST-GND}$.............................. -0.3V to V_{SW} + 6.5V
V_{HGP}, V_{HGN}.................. SW - 0.3V to V_{BST} + 0.3V
V_{LGP}, V_{LGN}.......................... -0.3V to V_{CC} + 0.3V
PWMH, PWML...............................-0.3V to 6.5V
Junction temperature................................ 150°C
Lead temperature ....260°C
Storage temperature.................-65°C to +150°C

ESD Ratings

Human body model (HBM) .... ±2000V
Charged-device model (CDM) .... ±2000V

Recommended Operating Conditions [2]

Supply voltage (V_{CC})........................4.5V to 5.5V
PWMH, PWML..................................0V to 5.5V
SW.. -5V to +100V
BST.............................. V_{SW} + 4V to V_{SW} + 5.5V
Operating junction temp (T_J)….-40°C to +125°C

Thermal Resistance [3]   θ$_{JA}$ θ$_{JC}$

QFN-14 (3mmx3mm).............55.5 .... 3.4 .. °C/W

Notes:

1) Exceeding these ratings may damage the device.
2) The device is not guaranteed to function outside of its operating conditions.
3) Measured on JESD51-7, 4-layer PCB. The value of θ$_{JA}$ given in this table is only valid for comparison with other packages and cannot be used for design purposes. These values were calculated in accordance with JESD51-7, and simulated on a specified JEDEC board. They do not represent the performance obtained in an actual application.

ELECTRICAL CHARACTERISTICS

V$_{CC}$ = 5V, T$_A$ = 25°C for typical values and T$_J$ = -40°C to 125°C for min and max values, unless otherwise noted.

Parameter	Symbol	Condition	Min	Typ	Max	Units
VCC Supply						
VCC quiescent current	I$_Q$	PWMH = PWML = 0		110	170	µA
VCC operation current	I$_{VCC}$	No load on HGP and HGN or LGP and LGN, f$_{SW}$ = 500kHz		1	2	mA
V$_{CC}$ under-voltage lockout (UVLO) threshold rising	VCC$_{VTH}$		3.7	4.1	4.5	V
V$_{CC}$ UVLO threshold hysteresis	VCC$_{HYS}$			350		mV
Pulse-Width Modulation (PWM) Input						
PWM logic high voltage	V$_{H\_PWM}$		1.7	1.9		V
PWM threshold hysteresis	V$_{HYS\_PWM}$			400		mV
PWM logic low voltage	V$_{L\_PWM}$			1.5	1.6	V
PWM input pull-down resistance	R$_{PWM\_IN}$		100	200	300	kΩ
High-Side (HS) Driver Supply						
V$_{BST-SW}$ UVLO threshold rising	VBST$_{VTH}$		80%	86%	92%	V$_{CC}$
V$_{BST-SW}$ UVLO threshold hysteresis	VBST$_{VTH\_HYS}$			7%		V$_{CC}$
Bootstrap Function						
Dynamic resistance	R$_{BST\_RES}$		2	4	6	Ω
BST - SW clamp voltage	V$_{BST\_CLAMP}$	V$_{BST\_CLAMP}$ = V$_{BST}$ − V$_{SW}$		106%		V$_{CC}$
HS and Low-Side (LS) Gate Driver						
Peak source current [4]	I$_{SOURCE}$	V$_{HGP-SW}$ = 2V, V$_{LGP-LS}$ = 2V		1.6		A
Peak sink current [4]	I$_{SINK}$	V$_{HGN-SW}$ = 2V, V$_{LGN-LS}$ = 2V		5		A
Source resistance	R$_{SOURCE}$	I$_{SOURCE}$ = 100mA		1.2	2	Ω
Sink resistance	R$_{SINK}$	I$_{SINK}$ = 100mA		0.27	0.5	Ω
HS and LS Gate Driver Timing Characteristics						
HGP rising time (0.5V - 4.5V) [4]	t$_{R\_SW}$	1nF load		5		ns
HGL falling time (4.5V - 0V) [4]	t$_{F\_SW}$	1nF load		3		ns
LGP rising time (0.5V - 4.5V) [4]	t$_{R\_LS}$	1nF load		5		ns
LGN falling time (4.5V - 0.5V) [4]	t$_{F\_LS}$	1nF load		3		ns
HGP turn-on propagation delay	t$_{HPH}$	1nF load, PWMH rising to HGP rising		20	30	ns
HGN turn-off propagation delay	t$_{HPL}$	1nF load, PWMH falling to HGN falling		20	30	ns
LGP turn-on propagation delay	t$_{LPH}$	1nF load, PWML rising to LGP rising		20	30	ns

ELECTRICAL CHARACTERISTICS *(continued)*

V_{CC} = 5V, T_A = 25°C for typical value and T_J = -40°C to 125°C for min and max values, unless otherwise noted.

Parameter	Symbol	Condition	Min	Typ	Max	Units
LGN turn-off propagation delay	t_{LPL}	1nF load, PWML falling to LGN falling		20	30	ns
LGP on and HGN off delay matching	t_{OFF_M}			1.5	6	ns
LGN off and HGP on delay matching	t_{ON_M}			1.5	6	ns
Minimal input PWM pulse [4]	t_{PWM_MIN}			10		ns
Minimal gate output pulse [4]	t_{GATE_MIN}			15		ns
Thermal Protection						
Thermal shutdown [4]	T_{SD}			170		°C
Thermal shutdown hysteresis [4]	T_{SD_HYS}			30		°C

Note:

4) Guaranteed by design or characterization data. Not tested in production.

TIMING DIAGRAMS
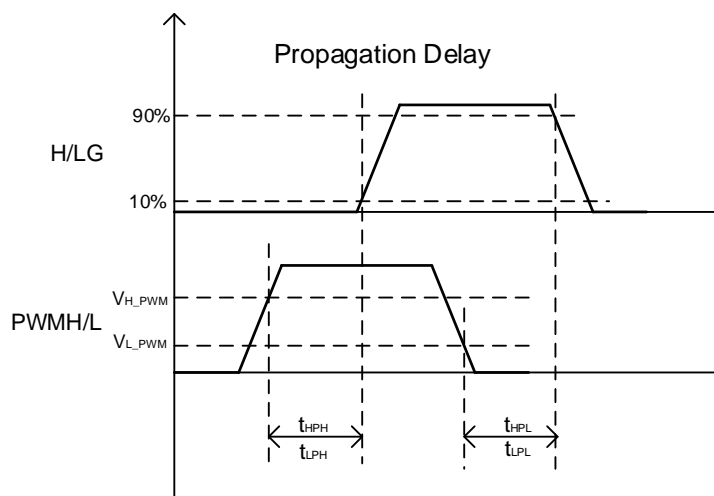
Figure 1: Propagation Delay
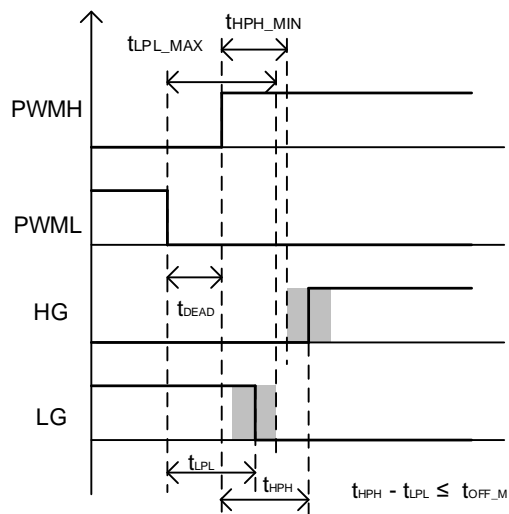
Figure 2: Propagation Delay Matching

TYPICAL CHARACTERISTICS

V$_{CC}$ = 5V, T$_A$ = 25°C, unless otherwise noted.
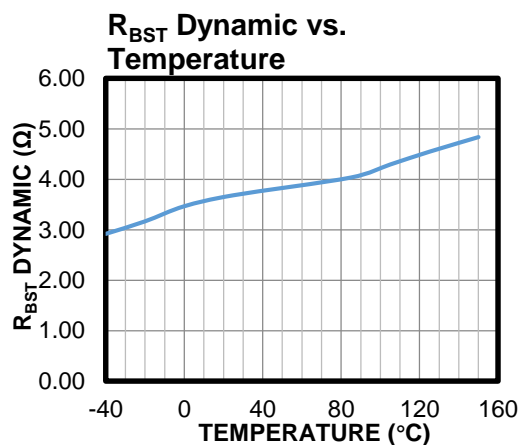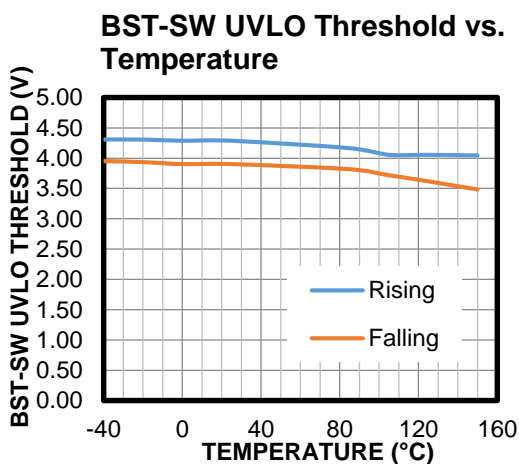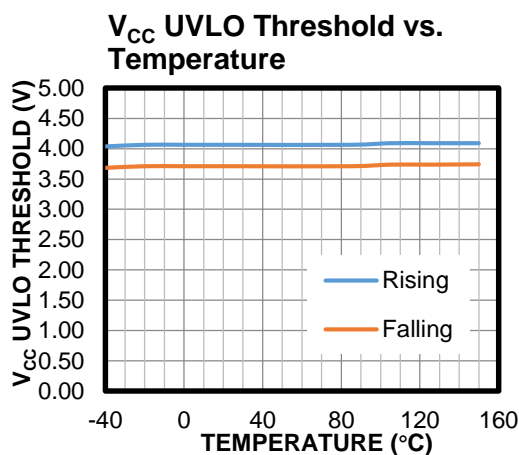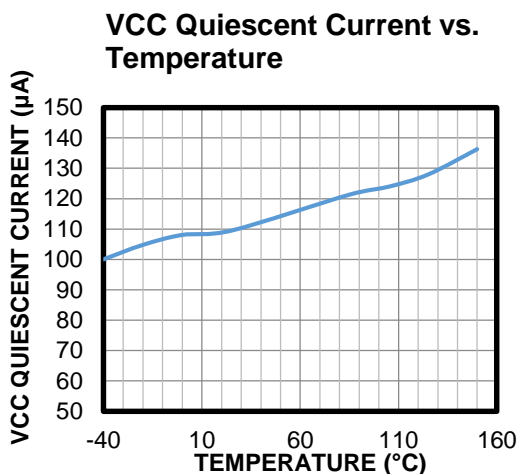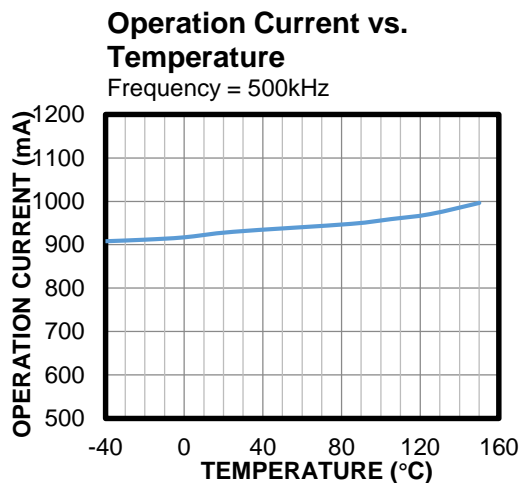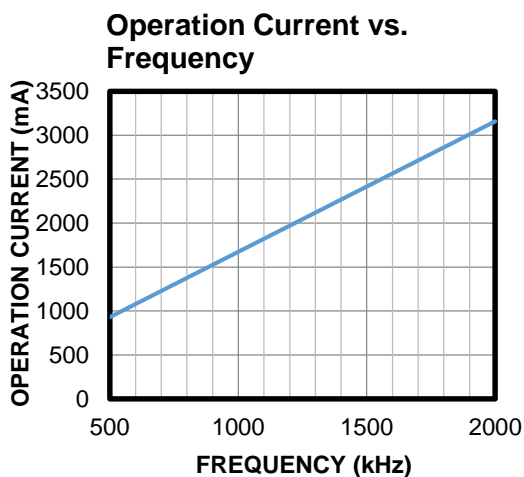
Operation Current vs. Frequency

Operation Current vs. Temperature
Frequency = 500kHz

VCC Quiescent Current vs. Temperature

V$_{CC}$ UVLO Threshold vs. Temperature

BST-SW UVLO Threshold vs. Temperature

R$_{BST}$ Dynamic vs. Temperature

TYPICAL CHARACTERISTICS *(continued)*

V_{CC} = 5V, T_A = 25°C, unless otherwise noted.

Propagation Delay vs. Temperature

Propagation Delay vs. Temperature
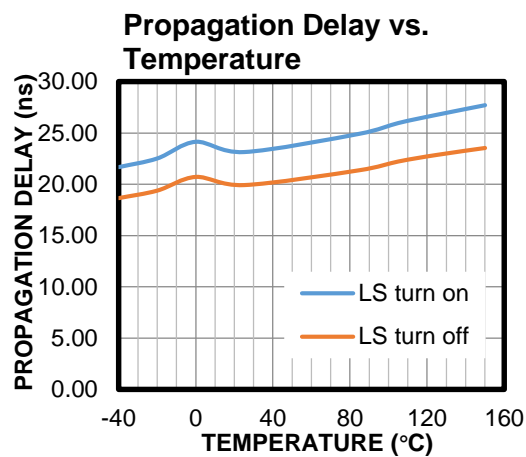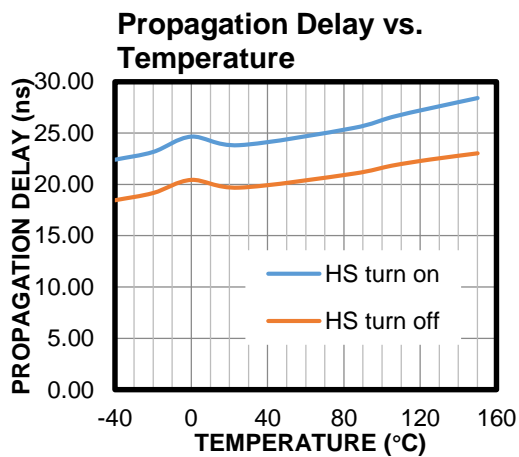
TYPICAL CHARACTERISTICS *(continued)*

Performance curves and waveforms are tested on the evaluation board, f_{SW} =1MHz, L = 2.2µH, T_A = 25°C, unless otherwise noted.

Steady State
V_{IN} = 48V, V_{OUT} = 12V, I_{OUT} = 2A
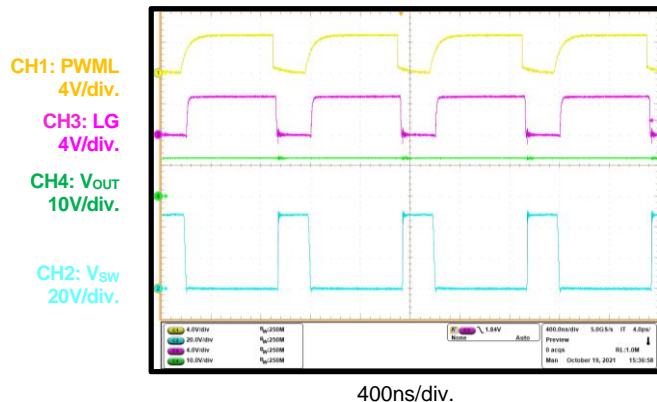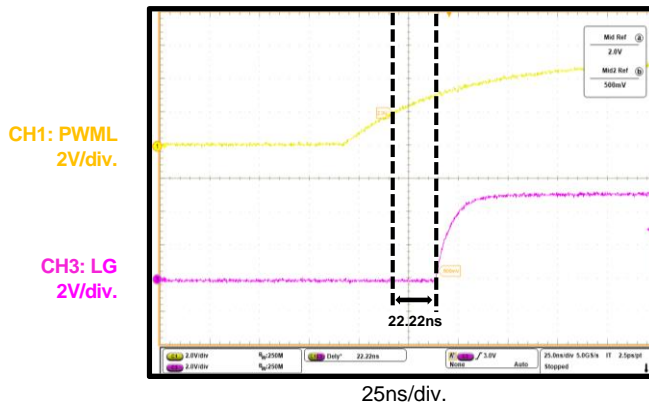
CH1: PWML 4V/div.
CH3: LG 4V/div.
CH4: V_{OUT} 10V/div.
CH2: V_{SW} 20V/div.

400ns/div.

LG Start-Up Propagation Delay
V_{IN} = 0V, V_{CC} = 5V

CH1: PWML 2V/div.
CH3: LG 2V/div.

22.22ns

25ns/div.

LG Shutdown Propagation Delay
V_{IN} = 0V, V_{CC} = 5V

CH1: PWML 2V/div.
CH3: LG 2V/div.

20.53ns

12.5ns/div.

HG Start-Up Propagation Delay
V_{IN} = 0V, V_{CC} = 5V

CH2: PWMH 2V/div.
CH4: HG 2V/div.

20.95ns

25ns/div.

HG Shutdown Propagation Delay
V_{IN} = 0V, V_{CC} = 5V

CH2: PWMH 2V/div.
CH4: HG 2V/div.

20.34ns
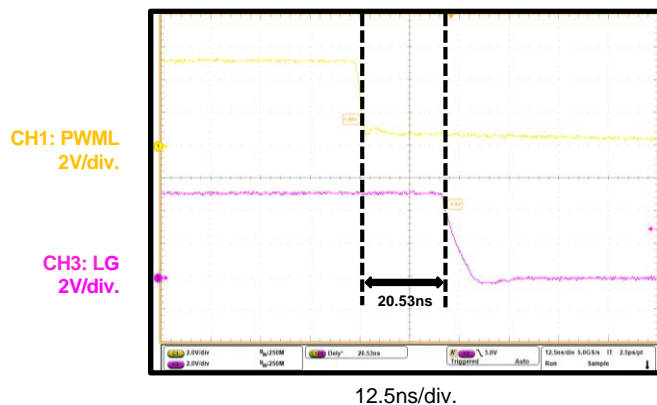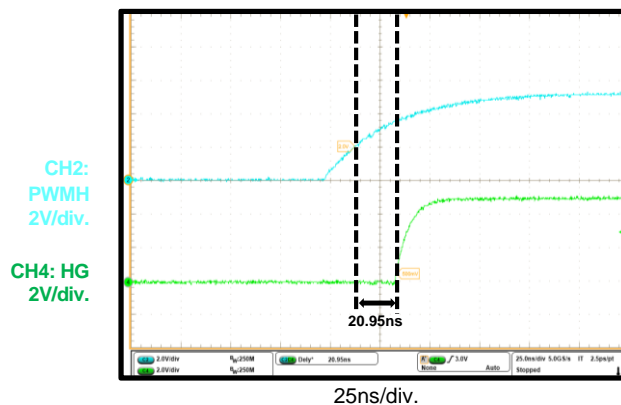
12.5ns/div.
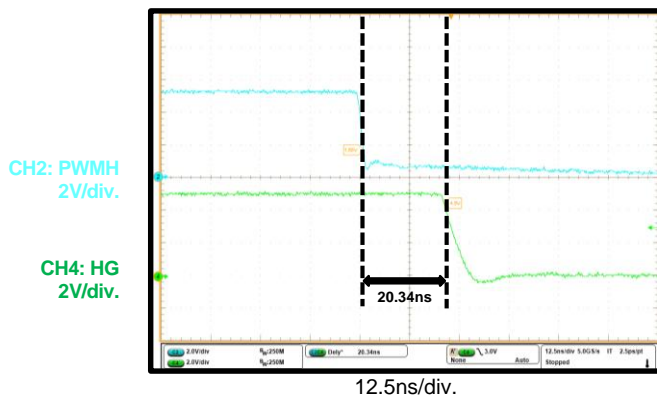
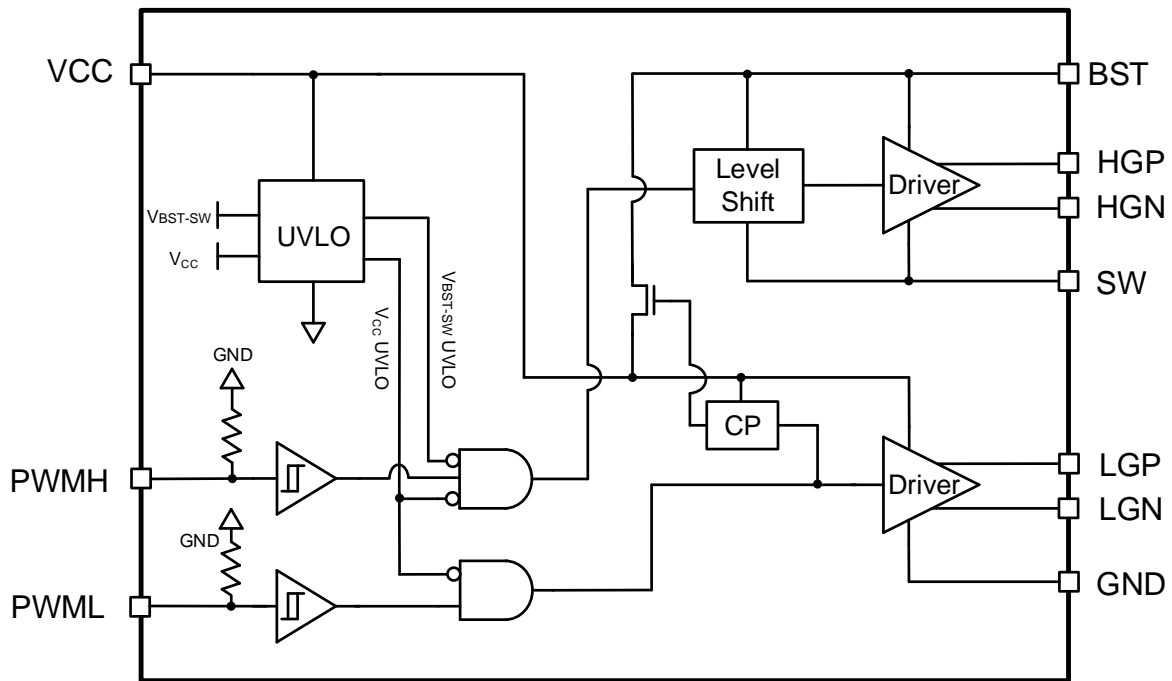# FUNCTIONAL BLOCK DIAGRAM

Figure 3: Functional Block Diagram

OPERATION

The MP1918 is designed to drive both high-side (HS) and low-side (LS) enhancement mode GaN FETs or N-channel MOSFETs. The floating HS bias voltage can support a bus voltage up to $100V_{DC}$. The new bootstrap (BST) charging technology prevents the HS driver voltage from exceeding the VCC voltage (V_{CC}), which prevents the gate voltage from exceeding the GaN FET's maximum gate-to-source voltage rating.

Pulse-Width Modulation (PWM) Input and Output

The PWMH and PWML pins are logical inputs that can be independently controlled and withstand voltages up to 5.5V. The input PWM can be floated if it is not used. If both PWMH and PWML control the high-side MOSFETs (HS-FETs) and low-side MOSFETs (LS-FETs) of the same bridge, then they prevent shoot-through by setting a sufficient dead time between PWMH and PWML (see Figure 4).

The output's pull-down and pull-up resistance are optimized for enhancement mode GaN FETs to achieve high frequency and efficient operation. The 0.27Ω pull-down resistance provides a robust, low-impedance turn-off path

to eliminate an accidental turn-on due to a high change in voltage or change in current with respect to time (dV/dt or dI/dt, respectively). The 1.2Ω pull-up resistance reduces the switch node voltage's ringing and overshoot.
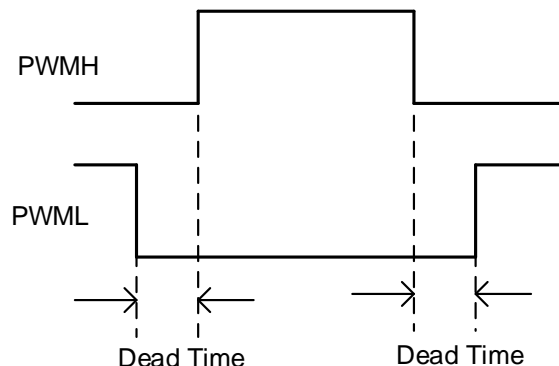
Figure 4 shows the timing for the dead time.

Figure 4: Dead Time Timing

The separate gate outputs means that the MP1918 can add different gate loop resistors to adjust the turn-on and turn-off speeds.

Table 1 shows a truth table between the inputs and outputs.

Table 1: HG and LG Truth Table

PWMH	PWML	HGP	HGN	LGP	LGN
High	Low	High	Open	Open	Low
Low	High	Open	Low	High	Open
High	High	High	Open	High	Open
Low	Low	Open	Low	Open	Low

Under-Voltage Lockout (UVLO)

The MP1918 employs both V_{CC} and V_{BST-SW} under-voltage lockout (UVLO).

When V_{CC} is below its UVLO threshold (VCC_{VTH}), both PWMH and PWML are ignored.

When the BST-SW voltage (V_{BST-SW}) is below its UVLO threshold ($VBST_{VTH}$), PWMH is ignored and the HG pulls low, but the LG responds with PWML.

When $V_{BST-SW} > VBST_{VTH}$ and $V_{CC} > VCC_{VTH}$, both HG and LG work. Table 2 on page 13 shows the UVLO PWM distribution logic, where 1 means "high" and 0 means "low".

Table 2: VCC and V_{BST-SW} UVLO PWM Distribution Logic

V_{CC} Condition	V_{BST-SW} Condition	PWMH	PWML	HG	LG
$V_{CC} < VCC_{VTH}$	Any	1	0	0	0
		0	1	0	0
		1	1	0	0
		0	0	0	0
$V_{CC} > VCC_{VTH}$	$V_{BST-SW} < VBST_{VTH}$	1	0	0	0
		0	1	0	1
		1	1	0	1
		0	0	0	0
	$V_{BST-SW} > VBST_{VTH}$	1	0	1	0
		0	1	0	1
		1	1	1	1
		0	0	0	0

Bootstrap (BST) Clamping

Due to the intrinsic feature of the enhancement mode GaN FETs, the source-to-drain voltage of the low-side MOSFET (LS-FET) typically exceeds the diode's forward voltage drop when the gate pulls low. This causes a negative voltage on the SW pin. Moreover, the negative voltage transient on SW can be significantly high, depending on the layout and the parasitic inductances of the device's drain and source.

When the HS driver uses the floating bootstrap configuration, a negative SW voltage can lead to an excessive bootstrap voltage, which can damage the HS GaN FET.

The MP1918 employs a new charging logic only when PWML = 1. In this scenario, V_{BST-SW} charges from V_{CC}. There is no current path from VCC to BST when PWML = 0, so V_{BST-SW} is always below V_{CC}. In addition, the electrostatic discharge (ESD) between BST and SW also clamps V_{BST-SW} such that it does not exceed 6V.

APPLICATION INFORMATION

PCB Layout Guidelines

Efficient PCB layout is critical for stable operation. For the best results, refer to Figure 5 and follow the guidelines below:

1. Place the MP1918 as close as possible to the GAN FETs to reduce the loop inductance and minimize noise.

2. Divide the pins of the MP1918 into three blocks according to their functions.

   a. PWMH/L and VCC (pin 10) refer to the AGND.

   b. LGP/N and VCC (pin 14) refer to the PGND.

   c. HGP/N and BST refer to the SW.

3. Place a 0Ω resistor between AGND and PGND in the bottom layer.

4. Low-ESR/ESL bypass capacitors must be connected as close as possible to the MP1918 (between the VCC and GND pins, and between the BST and SW pins) to support the high peak current being drawn from VCC when the GaN/MOSFETs turn on.

5. Use a Kelvin connection between the MP1918 and GAN FETs to minimize the common source inductance.
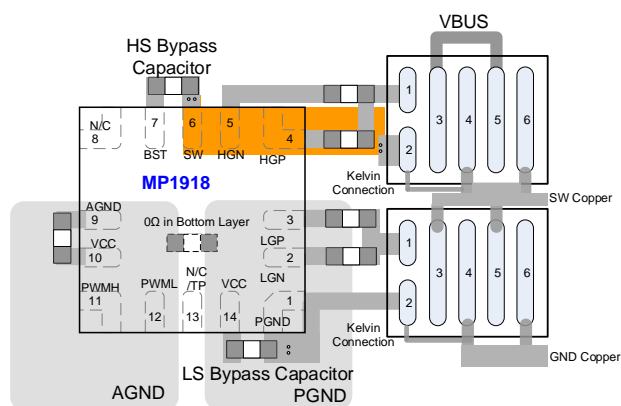
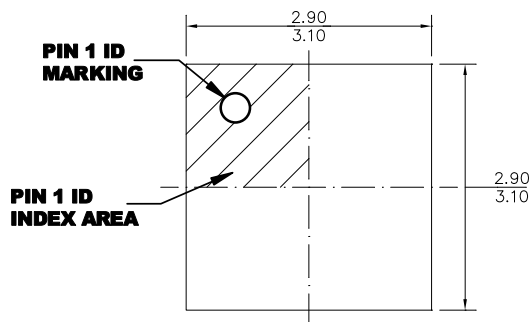**Figure 5: Recommended PCB Layout**
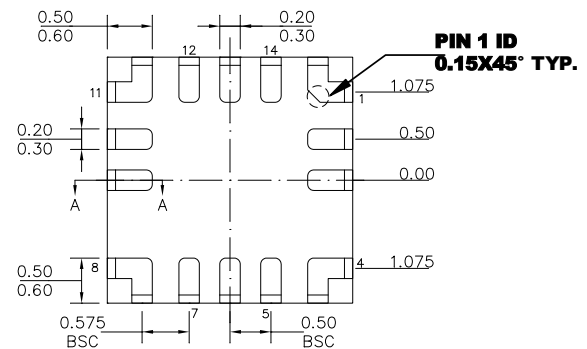
TYPICAL APPLICATION CIRCUIT
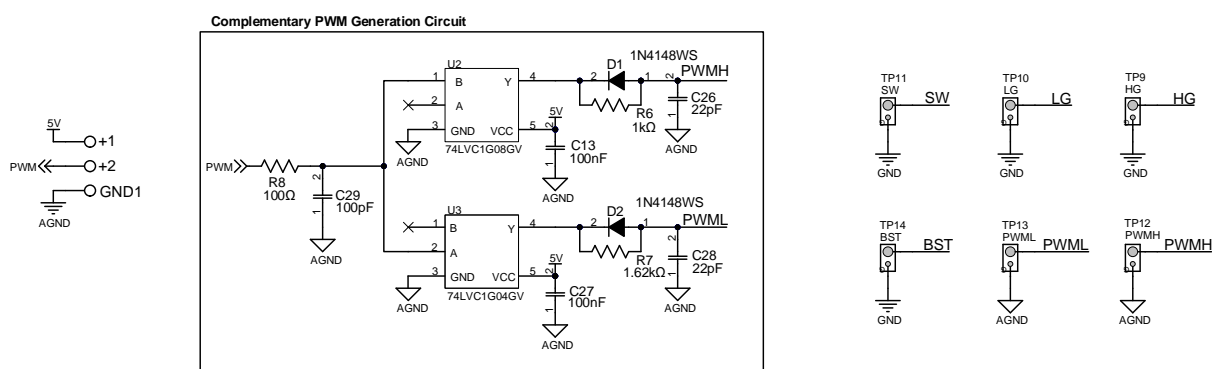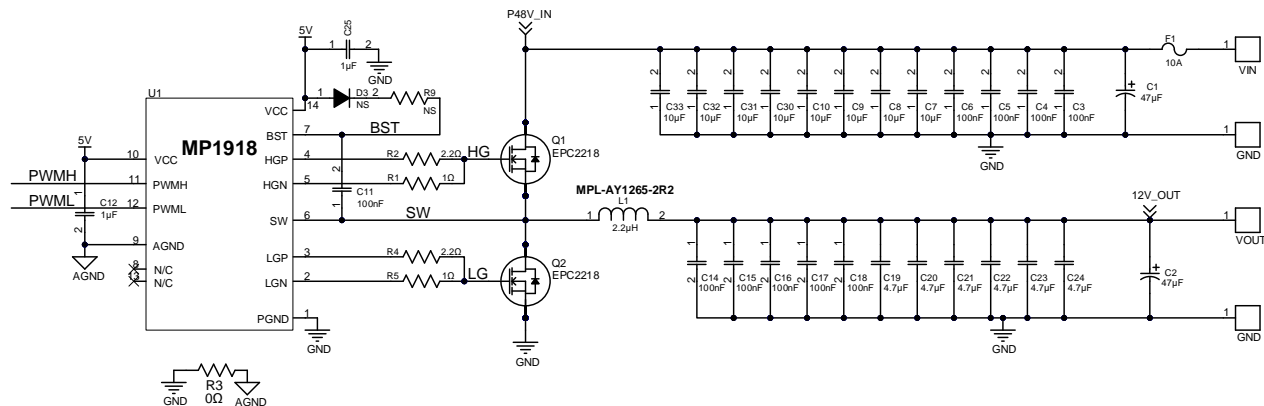
Figure 6: Typical Application Circuit (Reference Design)
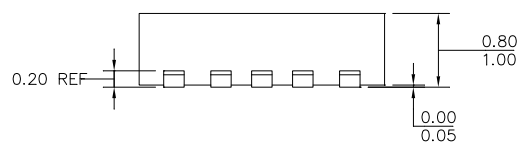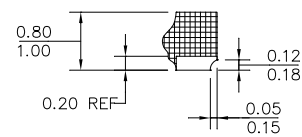
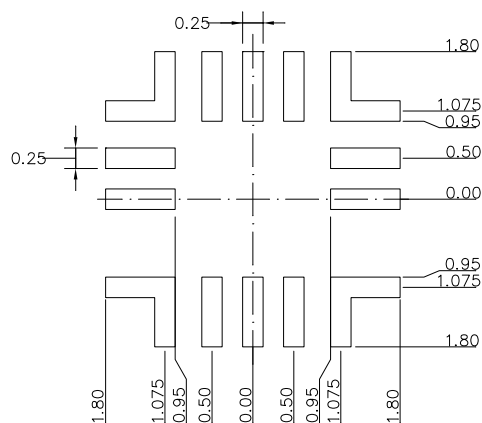# PACKAGE INFORMATION

QFN-14 (3mmx3mm)
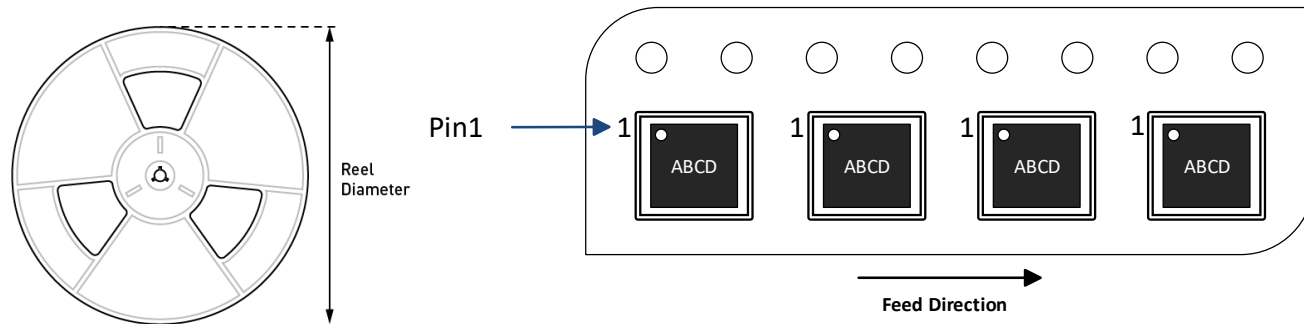

TOP VIEW

BOTTOM VIEW

SIDE VIEW

SECTION A-A

RECOMMENDED LAND PATTERN

NOTE:

1) THE LEAD SIDE IS WETTABLE.
2) ALL DIMENSIONS ARE IN MILLIMETERS.
3) LEAD COPLANARITY SHALL BE 0.08 MILLIMETERS MAX.
4) JEDEC REFERENCE IS MO-220.
5) DRAWING IS NOT TO SCALE.

CARRIER INFORMATION

Reel Diameter

Pin1 → 1

Feed Direction

Part Number	Package Description	Quantity/ Reel	Quantity/ Tube	Quantity/ Tray	Reel Diameter	Carrier Tape Width	Carrier Tape Pitch
MP1918GQE-Z	QFN-14 (3mmx3mm)	5000	N/A	N/A	13in	12mm	8mm

REVISION HISTORY

Revision #	Revision Date	Description	Pages Updated
1.0	5/5/2023	Initial Release	-